Search Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/734,420	LEE ET AL.	
Examiner	Art Unit	
Iohn P Trimmings	2138	

	SEARCHED		
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1	*** ****	
		<u> </u>	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
NPL Search: BIST, JTAG, memory test, authors.	4/18/2006	JPT
Dble Patent Search: Negative.	4/18/2006	JPT
Class Search: 714/30,25,710,711,718, 719,723,733,734. Text strategy attached.	4/18/2006	JPT